



PATENT

UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.: 10/791,629

Filing Date: March 3, 2004

Applicant: Soo-Chan LEE et al.

Group Art Unit: 2829

Examiner: Jermele M. Hollington

Title: SYSTEM AND METHOD FOR TESTING SEMICONDUCTOR
DEVICES

Attorney Docket: 2421-000033/US

Customer Service Window
Randolph Building
401 Dulany Street
Alexandria, VA 22314
Mail Stop RCE

April 27, 2007

**REQUEST FOR CONTINUED EXAMINATION
AND AMENDMENT UNDER 37 C.F.R. § 1.114**

Sir:

In response to the Final Office Action mailed December 27, 2006, the due date having been extended one (1) month, the following amendments and remarks are respectfully submitted in connection with the above-identified application.

Listing of the Claims begin on page 2 of this Amendment.

Remarks begin on page 16 of this Amendment.

	Claims remaining after Amendment		Highest number previously paid for		Present extra
Total	40	-	42	=	0
Independent	13	-	13	=	0

04/30/2007 DEMMANU1 00000015 10791629

02 FC:1251

120.00 0P